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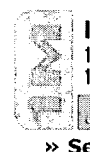
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<u>L10</u>	L9 not l6	26	<u>L10</u>
<u>L9</u>	L8 and (knowledge adj base)	28	<u>L9</u>
<u>L8</u>	L7 and (design\$ near3 file\$)	104	<u>L8</u>
<u>L7</u>	l1 and cad	440	<u>L7</u>
<u>L6</u>	l3 or L5	40	<u>L6</u>
<u>L5</u>	L1 and (manufactur\$ near3 knowledge\$)	23	<u>L5</u>
<u>L4</u>	L1 and knowledge	2076	<u>L4</u>
<u>L3</u>	l1 and L2	20	<u>L3</u>
<u>L2</u>	design\$ near3 file\$ near7 database\$	464	<u>L2</u>
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*Butz, B.P.; Palumbo, N.F.; Unterberger, R.C., Jr.; Miller, D.G.; Rushing, G.L.;*  
 Systems, Man and Cybernetics, 1992., IEEE International Conference on , 18-  
 Oct. 1992

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17 **A novel approach to knowledge-based communication system desi**
*Edrich, M.;*

 Artificial Intelligence for Applications, 1992., Proceedings of the Eighth Confer-  
 on , 2-6 March 1992

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18 **LED: an educational tool for electric circuit design**
*Di Cataldo, G.; Nunnari, G.;*

 Electrotechnical Conference, 1989. Proceedings. 'Integrating Research, Indus-  
 and Education in Energy and Communication Engineering', MELECON '89.,  
 Mediterranean , 11-13 April 1989

Pages:755 - 758

[\[Abstract\]](#)    [\[PDF Full-Text \(212 KB\)\]](#)    **IEEE CNF**
19 **Development of a knowledge-based (expert) system (PECT) for po-  
electronic circuit design**
*Cumbi, M.J.N.; Shepherd, D.W.; Hulley, L.N.;*

 Power Electronics and Applications, 1993., Fifth European Conference on , 13-  
 Sep 1993

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20 **Reactive constraint-based scheduling**

*Elleby, P.; Fargher, H.E.; Addis, T.R.;*

Artificial Intelligence in Planning for Production Control, IEE Colloquium on , 2  
1988

Pages:4/1 - 4/5

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